

Search Notes

Application/Control No.

10/555,646

Examiner

Nguyen N. Hanh

Applicant(s)/Patent under
Reexamination

VASILESCU ET AL.

Art Unit

2834

SEARCHED

Class	Subclass	Date	Examiner
310	52	4/4/2007	HN
310	54	4/4/2007	HN
310	58	4/4/2007	HN
310	64	4/4/2007	HN

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner